



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Heyman, et al.

Atty. Ref.: 4271-32

Serial No. 10/816,667

TC/A.U.: 2855

Filed: April 2, 2004

Examiner: Noori, Max H.

Allowed: July 21, 2005

Confirmation No. 9691

For: BOND TESTING SYSTEM, METHOD, AND APPARATUS

* * * * *

August 31, 2005

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449.

- ☐ All listed documents are attached.
- ☒ Copies of U.S. Patent Publications are not required and are not attached.
- ☒ Listed foreign patent publications and other documents are enclosed.
- ☐ The listed documents were cited in the ISR and copies should have been

supplied by WIPO directly to the US PTO. If copies are not timely received from WIPO, please telephone the undersigned so that copies can be timely supplied for the Examiner's consideration in this US National Phase Application.


This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO/SB/08a and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Heyman, et al.
Serial No. 10/816,667

Respectfully submitted,

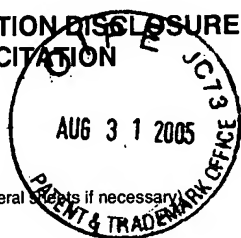
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INFORMATION DISCLOSURE
CITATION

(Use several sheets if necessary)



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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,237,516	08/1993	Heyman			
	4,843,346	06/1989	Heyman, et al.			
	4,624,142	11/1986	Heyman			
	4,363,242	12/1982	Heyman			
	4,117,731	10/1978	Heyman			
	4,062,227	12/1977	Heyman			
	4,015,464	04/1977	Miller, et al.			

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	Provisional Patent Application of Heyman et al.; "A Differential Guided Wave Nonlinear Spectroscopy System;" Serial No. 60/476,218; filed June 6, 2003.
	Patent Application of Heyman et al.; "Method and Apparatus for Determining and Assessing a Characteristic of a Material;" Serial No. 10/860,636; filed June 4, 2004.
	Joseph S. Heyman; "Residual Stress Characterization with a Magnetic/Ultrasonic Technique;" proceedings of IEEE, 1984 Ultrasonics Symposium, Dallas, TX; Nov. 14-16, 1984; pages 950-954.
	Sidney G. Allison, Joseph S. Heyman, and K. Salama; "Ultrasonic Measurement of Residual Deformation Stress in Thin Metal Plates Using Surface Acoustic Waves;" proceedings of IEEE 1983 Symposium, Atlanta, GA; Oct. 31-Nov. 2, 1983; pages 995-999.
	Joseph S. Heyman and Larry L. Yoder; "An Interferometric Measurement of the Acoustoelastic Constant of Rock Core Samples;" proceedings of IEEE, 1983 Symposium, Atlanta, GA; Oct. 31-Nov. 2, 1983; pages 980-983.
	Joseph S. Heyman and Wolfgang Issler; "Ultrasonic Mapping of Internal Stresses;" proceedings of IEEE 1982 Ultrasonics Symposium, San Diego, CA; Oct. 27-29, 1982; pages 893-897.
	Joseph S. Heyman; "A CW Ultrasonic Bolt-Strain Monitor;" SESA Experimental Mechanics, 17; 1977; page 183.
	J.E. Lynch, J.S. Heyman, and A.R. Hargens; "Ultrasonic Device for the Noninvasive Diagnosis of Compartment Syndrome;" Physiological Measurement, Vol. 25, Issue 1, 2004; pages N1-N9.
	Robert S. Rogowski, Milford S. Holben, Patrick Sullivan, and Joseph S. Heyman; "A Method for Monitoring Strain in Large Structures: Optical and Radio Frequency Devices;" presented at the Review of Progress in Quantitative Nondestructive Evaluation, Williamsburg, VA; June 21-26, 1987; pages 559-563.
	Sidney G. Allison, Joseph S. Heyman, Min Namkung, and K. Salama; "Ultrasonic Characterization of Plastic Deformation in Metals;" Review of Progress in Quantitative NDE; Plenum Press, New York (1986); pages 1565-1573.
	"Pulsed Phase-Locked-Loop Strain Monitor" A high-resolution, fully-automated strain monitor; NASA Tech Brief; Langley Research Center, Hampton, VA; Spring 1981, B-81-10068, LAR-12772.
	S.G. Allison, J. S. Heyman, K. Smith, and K. Salama; "Effect of Prestrain Upon Acoustoelastic Properties of Carbon Steel;" 1984 Ultrasonics Symposium; NASA Langley Research Center, Hampton, VA; pages 997-1002.
	J. Frankel and W. Scholz; "Ultrasonic Studies of Stresses and Plastic Deformation in Steel During Tension and Compression;" US Army Armament Research, Development, & Engineering Ctr., Watervliet, NY; pages 1577-1584.

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

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J. S. Heyman, S. G. Allison, and K. Salama; "Influence of Carbon Content on Higher-Order Ultrasonic Properties in Steels;" 1983 Ultrasonics Symposium; NASA-Langley Research Center, Hampton, VA; University of Houston, TX; pages 991-994.

M. Namkung, R. DeNale, and D. Utrata; "Uniaxial Stress and Wave Mode Dependence of Magnetoacoustic Responses in Iron-Base Alloys;" NASA Langley Research Center, Hampton, VA.

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